

Search Notes

Application/Control No.

10/814,617

Examiner

Khanh V. Nguyen

Applicant(s)/Patent under
Reexamination

BOCOCK ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	127	12/9/2004	NKV
330	129		
330	207P		
330	279		
330	285		
330	296		
330	297		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR